What is claimed is:

A method of manufacturing an oriented sintered ceramic product, which comprises dispersing a non-ferromagnetic powder having a not-cubic system crystal structure into a solvent, solidifying to mold the slurry in a magnetic field and then sintering the same.

- 2. A method of manufacturing an oriented sintered ceramic product as defined in claim 1, wherein the non-ferromagnetic powder is a non-cubic system ceramic powder.
- 3. A method of manufacturing an oriented sintered ceramic product as defined in claim 2, wherein the ceramic powder comprises an alumina powder, titanium dioxide powder, aluminum nitride powder, tetragonal zirconia powder, zinc oxide powder, tin oxide powder or hydroxyapatite powder, or a composite mixture containing them.
- 4. An oriented sintered ceramic product obtained by the manufacturing method as defined in any one of claims 1 to 3.

which (006) diffraction intensity is 1.2 times or more as (110) diffraction intensity in accordance with X-ray diffractiometry at a surface on which the C plane of alumina crystal is oriented, the average crystal grain size is 20 µm or less at the surface parallel with the

surface on which the C plane is oriented, or the average crystal grain size is 20  $\mu m$  or more and an aspect ratio of the crystal grain size is 0.4 or greater and 1 or less at a surface vertical perpendicular to the surface on which the C plane is oriented.

- 6. An oriented sintered titanium dioxide ceramic product which is a crystal oriented sintered titanium dioxide product.
- 7. An oriented sintered titanium dioxide ceramic product as defined in claim 6, which is a crystal oriented sintered rutile structure titanium dioxide product in which (002) diffraction intensity is greater than (110) diffraction intensity in accordance with X-ray diffractiometry.
- 8. An oriented sintered tetragonal zirconia ceramic product which is a crystal oriented sintered tetragonal zirconia product.
- 9. A crystal oriented sintered tetragonal zirconia ceramic product as defined in claim 8 wherein (002) diffraction intensity is greater than (200) diffraction intensity in accordance with X-ray diffractiometry.

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